

Notice of References Cited	Application/Control No. 10/075,264	Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner Brian Jelinek	Art Unit 2615	Page 1 of 1

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	B	US-6,507,366	01-2003	Lee, Hee-Jong	348/352
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	M	US-			

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NON-PATENT DOCUMENTS

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